Distributed by:



www.Jameco.com + 1-800-831-4242

The content and copyrights of the attached material are the property of its owner.





Features

- · High speed
 - -10 ns
- Fast t_{DOE}
- · CMOS for optimum speed/power
- · Low active power
 - -467 mW (max, 12 ns "L" version)
- · Low standby power
 - -0.275 mW (max, "L" version)
- · 2V data retention ("L" version only)
- Easy memory expansion with CE and OE features
- · TTL-compatible inputs and outputs
- Automatic power-down when deselected

Functional Description

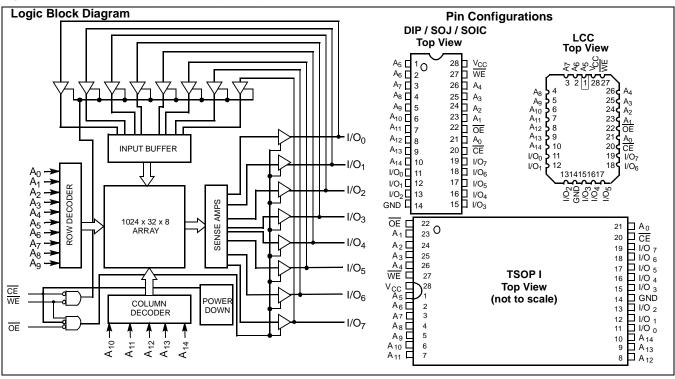
The CY7C199 is a high-performance CMOS static RAM organized as 32,768 words by 8 bits. Easy memory expansion

32K x 8 Static RAM

is provided by an active LOW Chip Enable ($\overline{\text{CE}}$) and active LOW Output Enable ($\overline{\text{OE}}$) and three-state drivers. This device has an automatic power-down feature, reducing the power consumption by 81% when deselected. The CY7C199 is in the standard 300-mil-wide DIP, SOJ, and LCC packages.

An active LOW Write Enable signal (\overline{WE}) controls the writing/reading operation of the memory. When \overline{CE} and \overline{WE} inputs are both LOW, data on the eight data input/output pins (I/O_0) through I/O_7 is written into the memory location addressed by the address present on the address pins (A_0) through A_{14} . Reading the device is accomplished by selecting the device and enabling the outputs, \overline{CE} and \overline{OE} active LOW, while \overline{WE} remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins are present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the chip is selected, outputs are enabled, and Write Enable (WE) is HIGH. A die coat is used to improve alpha immunity.



Selection Guide

| | | 7C199 -8 | 7C199 -10 | 7C199 -12 | 7C199 -15 | 7C199 -20 | 7C199 -25 | 7C199 -35 | 7C199 -45 | Unit |
|------------------------------|---|-------------|--------------|--------------|--------------|--------------|--------------|--------------|--------------|------|
| Maximum Access Time | | 8 | 10 | 12 | 15 | 20 | 25 | 35 | 45 | ns |
| Maximum Operating Current | | 120 | 110 | 160 | 155 | 150 | 150 | 140 | 140 | mΑ |
| | L | | 90 | 90 | 90 | 90 | 80 | 70 | | |
| Maximum CMOS Standby Current | | 0.5 | 0.5 | 10 | 10 | 10 | 10 | 10 | 10 | mΑ |
| | L | | 0.05 | 0.05 | 0.05 | 0.05 | 0.05 | 0.05 | | |

Shaded area contains advance information.



Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage Temperature-65°C to +150°C Ambient Temperature with Power Applied55°C to +125°C Supply Voltage to Ground Potential (Pin 28 to Pin 14)-0.5V to +7.0V

DC Voltage Applied to Outputs in High-Z State^[1].....-0.5V to V_{CC} + 0.5V

DC Input Voltage^[1].....-0.5V to V_{CC} + 0.5V

| Output Current into Outputs (LOW) | 20 mA |
|--|----------|
| Static Discharge Voltage(per MIL-STD-883, Method 3015) | > 2001V |
| Latch-up Current | > 200 mA |

Operating Range

| Range | Ambient Temperature ^[2] | V _{CC} |
|------------|------------------------------------|-----------------|
| Commercial | 0°C to +70°C | $5V \pm 10\%$ |
| Industrial | –40°C to +85°C | 5V ± 10% |
| Military | −55°C to +125°C | 5V ± 10% |

Electrical Characteristics Over the Operating Range (-8, -10, -12, -15)[3]

| | | | | 7C′ | 199-8 | 7C1 | 99-10 | 7C1 | 99-12 | 7C1 | 99-15 | |
|------------------|------------------------------------|--|---|------------|--------------------------|----------------|--------------------------|------------|--------------------------|----------------|--------------------------|------|
| Parameter | Description | Test Condition | Test Conditions | | Max. | Min. | Max. | Min. | Max. | Min. | Max. | Unit |
| V _{OH} | Output HIGH Voltage | V _{CC} = Min., I _{OH} =–4.0 mA | | 2.4 | | 2.4 | | 2.4 | | 2.4 | | V |
| V _{OL} | Output LOW Voltage | $V_{CC} = Min., I_{OL} = 8.0$ |) mA | | 0.4 | | 0.4 | | 0.4 | | 0.4 | V |
| V _{IH} | Input HIGH Voltage | | | 2.2 | V _{CC} +0.3V | 2.2 | V _{CC} +0.3V | 2.2 | V _{CC} +0.3V | 2.2 | V _{CC} +0.3V | V |
| V _{IL} | Input LOW Voltage | | | -0.5 | 0.8 | -0.5 | 0.8 | -0.5 | 0.8 | -0.5 | 0.8 | V |
| I _{IX} | Input Load Current | $GND \le V_1 \le V_{CC}$ | | - 5 | +5 | - 5 | +5 | - 5 | +5 | - 5 | +5 | μΑ |
| I _{OZ} | Output Leakage Current | GND \leq V _O \leq V _{CC} , Disabled | GND <u><</u> V _O <u><</u> V _{CC} , Output Disabled | | +5 | - 5 | +5 | - 5 | +5 | - 5 | +5 | μΑ |
| I _{CC} | V _{CC} Operating Supply | V _{CC} = Max., | Com'l | | 120 | | 110 | | 160 | | 155 | mΑ |
| | Current | $I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$ | L | | | | 85 | | 85 | | 100 | mA |
| | | I - IMAX - IMRC | Mil | | | | | | | | 180 | mA |
| I _{SB1} | Automatic CE | Max. V _{CC} , CE ≥ | Com'l | | 5 | | 5 | | 30 | | 30 | mA |
| | Power-down Current— TTL Inputs | $V_{IH}, V_{IN} \ge V_{IH} \text{ or } V_{IN} \le V_{IL}, f = f_{MAX}$ | L | | | | 5 | | 5 | | 5 | mA |
| I _{SB2} | Automatic CE | Max. V _{CC} , | Com'l | | 0.5 | | 0.5 | | 10 | | 10 | mA |
| | Power-down Current— CMOS Inputs | $CE \ge V_{CC} - 0.3V$ $V_{IN} \ge V_{CC} - 0.3V$ | L | | 0.05 | | 0.05 | | 0.05 | | 0.05 | mA |
| | Civico iriputo | or $V_{IN} \le 0.3V$, $f = 0$ | Mil | | | | | | | | 15 | mA |

Electrical Characteristics Over the Operating Range (-20, -25, -35, -45) [3]

| | | | | 7C1 | 99-20 | 7C1 | 99-25 | 7C1 | 99-35 | 7C199-45 | | |
|-----------------|----------------------------------|---|-----------------|----------------|--------------------------|----------------|--------------------------|----------------|--------------------------|----------------|--------------------------|------|
| Parameter | Description | Test Conditio | Test Conditions | | Max. | Min. | Max. | Min. | Max. | Min. | Max. | Unit |
| V _{OH} | Output HIGH Voltage | $V_{CC} = Min., I_{OH} = -$ | 4.0 mA | 2.4 | | 2.4 | | 2.4 | | 2.4 | | V |
| V _{OL} | Output LOW Voltage | $V_{CC} = Min., I_{OL} = 8$ | 3.0 mA | | 0.4 | | 0.4 | | 0.4 | | 0.4 | V |
| V _{IH} | Input HIGH Voltage | | | 2.2 | V _{CC} +0.3V | V |
| V _{IL} | Input LOW Voltage | | | -0.5 | 0.8 | -0.5 | 0.8 | -0.5 | 0.8 | -0.5 | 0.8 | V |
| I _{IX} | Input Load Current | $GND \le V_I \le V_{CC}$ | | - 5 | +5 | - 5 | +5 | – 5 | +5 | - 5 | +5 | μΑ |
| I _{OZ} | Output Leakage Current | GND $\leq V_1 \leq V_{CC}$, Ou Disabled | ıtput | - 5 | +5 | μΑ |
| I _{CC} | V _{CC} Operating Supply | V _{CC} = Max., | Com'l | | 150 | | 150 | | 140 | | 140 | mA |
| | Current | $I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$ | L | | 90 | | 80 | | 70 | | 70 | mA |
| | | I - IMAX - IMRC | Mil | | 170 | | 150 | | 150 | | 150 | mA |

Shaded area contains advance information.

Notes:

- 1. V_{IL} (min.) = -2.0V for pulse durations of less than 20 ns.
- 2. T_A is the "instant on" case temperature.
- 3. See the last page of this specification for Group A subgroup testing information.



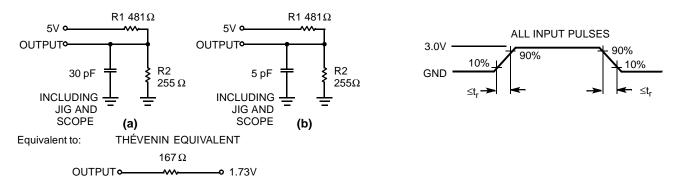
Electrical Characteristics Over the Operating Range (-20, -25, -35, -45) (continued)^[3]

| | | | | 7C1 | C199-20 7C199-2 | | 99-25 | 9-25 7C199-35 | | 7C199-45 | | |
|------------------|------------------------------------|---|-------|------|-----------------|------|-------|---------------|------|----------|------|------|
| Parameter | Description | Test Conditions | | Min. | Max. | Min. | Max. | Min. | Max. | Min. | Max. | Unit |
| I _{SB1} | Automatic CE | Max. V_{CC} , $\overline{CE} \ge V_{JH}$, | Com'l | | 30 | | 30 | | 25 | | 25 | mΑ |
| | Power-down Current— TTL Inputs | $V_{IN} \ge V_{IH} \text{ or } V_{IN} \le V_{IL},$ $f = f_{MAX}$ | L | | 5 | | 5 | | 5 | | 5 | mA |
| I _{SB2} | Automatic CE | Max. V _{CC} , | Com'l | | 10 | | 10 | | 10 | | 10 | mA |
| | Power-down Current— CMOS Inputs | $\label{eq:max_vcc} \begin{split} & \underline{\text{Max. V}_{\text{CC}}}, \\ & \underline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3\text{V} \\ & \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3\text{V} \text{ or} \end{split}$ | L | | 0.05 | | 0.05 | | 0.05 | | 0.05 | μΑ |
| | OMOG IIIpalo | $V_{IN} \le 0.3V, f=0$ | Mil | | 15 | | 15 | | 15 | | 15 | mA |

Capacitance^[4]

| Parameter | Description | Test Conditions | Max. | Unit |
|------------------|--------------------|---|------|------|
| C _{IN} | Input Capacitance | $T_A = 25^{\circ}C, f = 1 \text{ MHz},$ | 8 | pF |
| C _{OUT} | Output Capacitance | $V_{CC} = 5.0V$ | 8 | pF |

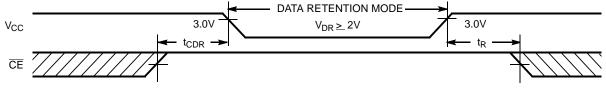
AC Test Loads and Waveforms^[5]



Data Retention Characteristics Over the Operating Range (L-version only)

| Parameter | Description | | Conditions ^[6] | Min. | Max. | Unit |
|---------------------------------|------------------------------------|-------------|---|------|------|------|
| V_{DR} | V _{CC} for Data Retention | | | 2.0 | | V |
| I _{CCDR} | Data Retention Current | Com'l | $V_{CC} = V_{DR} = 2.0V$, $\overline{CE} \ge V_{CC} - 0.3V$, $V_{IN} \ge V_{CC} - 0.3V$ or $V_{IN} \le V_{CC} - 0.3V$ | | | μΑ |
| | | Com'l L | $0.3V$, $v_{IN} \ge v_{CC} - 0.3V$ of $v_{IN} \le 0.3V$ | | 10 | μΑ |
| t _{CDR} ^[4] | Chip Deselect to Data Ret | ention Time | | 0 | | ns |
| t _R ^[5] | Operation Recovery Time | | | 200 | | μs |

Data Retention Waveform



Note:

- 4. Tested initially and after any design or process changes that may affect these parameters.
 5. t_R≤ 3 ns for the -12 and the -15 speeds. t_R≤ 5 ns for the -20 and slower speeds
 6. No input may exceed V_{CC} + 0.5V.



Switching Characteristics Over the Operating Range (-8, -10, -12, -15) [3, 7]

| | | 7C1 | 199-8 | 7C1 | 99-10 | 7C1 | 99-12 | 7C1 | 7C199-15 | |
|----------------------------|-------------------------------------|------|-------|------|-------|------|-------|------|----------|------|
| Parameter | Description | Min. | Max. | Min. | Max. | Min. | Max. | Min. | Max. | Unit |
| Read Cycle | | | | | | | | | • | |
| t _{RC} | Read Cycle Time | 8 | | 10 | | 12 | | 15 | | ns |
| t _{AA} | Address to Data Valid | | 8 | | 10 | | 12 | | 15 | ns |
| t _{OHA} | Data Hold from Address Change | 3 | | 3 | | 3 | | 3 | | ns |
| t _{ACE} | CE LOW to Data Valid | | 8 | | 10 | | 12 | | 15 | ns |
| t _{DOE} | OE LOW to Data Valid | | 4.5 | | 5 | | 5 | | 7 | ns |
| t _{LZOE} | OE LOW to Low-Z ^[8] | 0 | | 0 | | 0 | | 0 | | ns |
| t _{HZOE} | OE HIGH to High-Z ^[8, 9] | | 5 | | 5 | | 5 | | 7 | ns |
| t _{LZCE} | CE LOW to Low-Z ^[8] | 3 | | 3 | | 3 | | 3 | | ns |
| t _{HZCE} | CE HIGH to High-Z ^[8,9] | | 4 | | 5 | | 5 | | 7 | ns |
| t _{PU} | CE LOW to Power-up | 0 | | 0 | | 0 | | 0 | | ns |
| t _{PD} | CE HIGH to Power-down | | 8 | | 10 | | 12 | | 15 | ns |
| Write Cycle ^{[10} | 0, 11] | • | • | • | | • | | • | • | • |
| t _{WC} | Write Cycle Time | 8 | | 10 | | 12 | | 15 | | ns |
| t _{SCE} | CE LOW to Write End | 7 | | 7 | | 9 | | 10 | | ns |
| t _{AW} | Address Set-up to Write End | 7 | | 7 | | 9 | | 10 | | ns |
| t _{HA} | Address Hold from Write End | 0 | | 0 | | 0 | | 0 | | ns |
| t _{SA} | Address Set-up to Write Start | 0 | | 0 | | 0 | | 0 | | ns |
| t _{PWE} | WE Pulse Width | 7 | | 7 | | 8 | | 9 | | ns |
| t _{SD} | Data Set-up to Write End | 5 | | 5 | | 8 | | 9 | | ns |
| t _{HD} | Data Hold from Write End | 0 | | 0 | | 0 | | 0 | | ns |
| t _{HZWE} | WE LOW to High-Z ^[9] | | 5 | | 6 | | 7 | | 7 | ns |
| t _{LZWE} | WE HIGH to Low-Z ^[8] | 3 | | 3 | | 3 | | 3 | | ns |

Switching Characteristics Over the Operating Range (-20, -25, -35, -45)^[3, 7]

| | | 7C19 | 99-20 | 7C1 | 99-25 | 7C199-35 | | 7C199-45 | | |
|-------------------|-------------------------------------|------|-------|------|-------|----------|------|----------|------|------|
| Parameter | Description | Min. | Max. | Min. | Max. | Min. | Max. | Min. | Max. | Unit |
| Read Cycle | | | | | • | • | • | • | • | I. |
| t _{RC} | Read Cycle Time | 20 | | 25 | | 35 | | 45 | | ns |
| t _{AA} | Address to Data Valid | | 20 | | 25 | | 35 | | 45 | ns |
| t _{OHA} | Data Hold from Address Change | 3 | | 3 | | 3 | | 3 | | ns |
| t _{ACE} | CE LOW to Data Valid | | 20 | | 25 | | 35 | | 45 | ns |
| t _{DOE} | OE LOW to Data Valid | | 9 | | 10 | | 16 | | 16 | ns |
| t _{LZOE} | OE LOW to Low-Z ^[8] | 0 | | 0 | | 0 | | 0 | | ns |
| t _{HZOE} | OE HIGH to High-Z ^[8, 9] | | 9 | | 11 | | 15 | | 15 | ns |
| t _{LZCE} | CE LOW to Low-Z ^[8] | 3 | | 3 | | 3 | | 3 | | ns |
| t _{HZCE} | CE HIGH to High-Z ^[8, 9] | | 9 | | 11 | | 15 | | 15 | ns |
| t _{PU} | CE LOW to Power-up | 0 | | 0 | | 0 | | 0 | | ns |

Shaded area contains advance information.

- 7. Test conditions assume signal transition time of 3 ns or less for -12 and -15 speeds and 5 ns or less for -20 and slower speeds, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
 8. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZCE}, and t_{HZWE} is less than t_{LZWE} for any given device.
 9. t_{HZCE}, t_{HZCE}, and t_{HZWE} are specified with C_L = 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
 10. The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
 11. The minimum write cycle time for write cycle #3 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}.

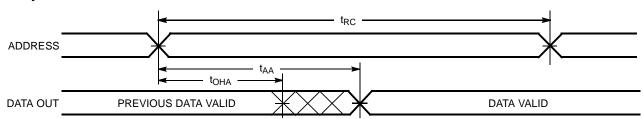


Switching Characteristics Over the Operating Range (-20, -25, -35, -45)[3, 7]

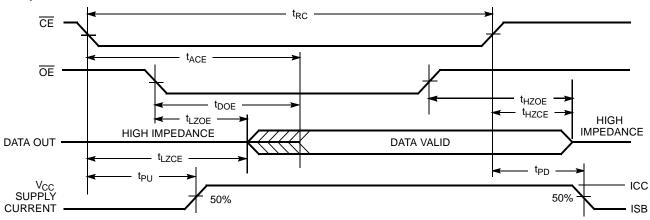
| | | 7C19 | 99-20 | 7C1 | 99-25 | 7C19 | 99-35 | 7C19 | 99-45 | |
|-------------------------------|---------------------------------|------|-------|------|-------|------|-------|------|-------|------|
| Parameter | Description | Min. | Max. | Min. | Max. | Min. | Max. | Min. | Max. | Unit |
| t _{PD} | CE HIGH to Power-down | | 20 | | 20 | | 20 | | 25 | ns |
| Write Cycle ^[10,] | 11] | | | | | | • | | • | |
| t _{WC} | Write Cycle Time | 20 | | 25 | | 35 | | 45 | | ns |
| t _{SCE} | CE LOW to Write End | 15 | | 18 | | 22 | | 22 | | ns |
| t _{AW} | Address Set-up to Write End | 15 | | 20 | | 30 | | 40 | | ns |
| t _{HA} | Address Hold from Write End | 0 | | 0 | | 0 | | 0 | | ns |
| t _{SA} | Address Set-up to Write Start | 0 | | 0 | | 0 | | 0 | | ns |
| t _{PWE} | WE Pulse Width | 15 | | 18 | | 22 | | 22 | | ns |
| t _{SD} | Data Set-up to Write End | 10 | | 10 | | 15 | | 15 | | ns |
| t _{HD} | Data Hold from Write End | 0 | | 0 | | 0 | | 0 | | ns |
| t _{HZWE} | WE LOW to High-Z ^[9] | | 10 | | 11 | | 15 | | 15 | ns |
| t _{LZWE} | WE HIGH to Low-Z ^[8] | 3 | | 3 | | 3 | | 3 | | ns |

Switching Waveforms

Read Cycle No. 1^[12, 13]



Read Cycle No. 2 [13, 14]



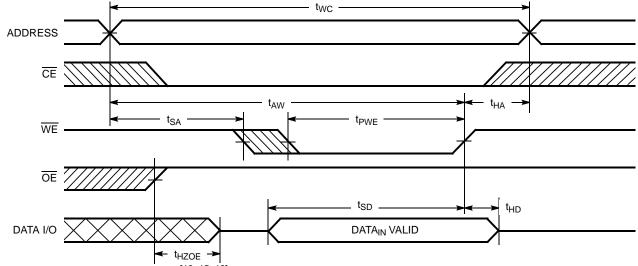
Notes:

- Device is continuously selected. OE, CE = V_{IL}.
 WE is HIGH for read cycle.
 Address valid prior to or coincident with CE transition LOW.

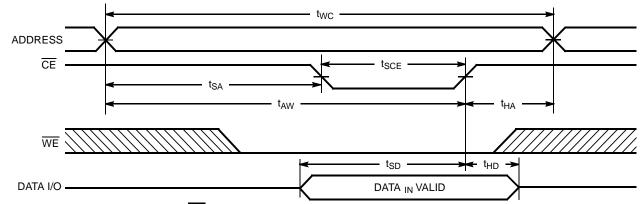


Switching Waveforms (continued)

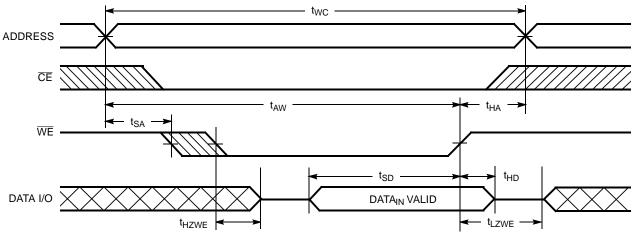
Write Cycle No. 1 (WE Controlled)^[10, 15, 16]



Write Cycle No. 2 (CE Controlled)^[10, 15, 16]



Write Cycle No. 3 (WE Controlled $\overline{\text{OE}}$ LOW)[11, 16]

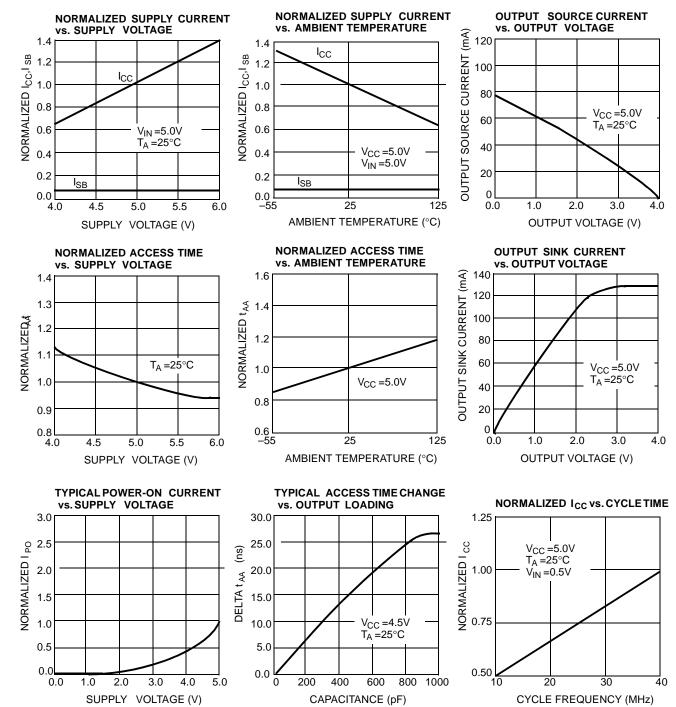


Notes:

15. Data I/O is high impedance if OE = V_{IH}.
 16. If CE goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.



Typical DC and AC Characteristics



Truth Table

| CE | WE | OE | Inputs/Outputs | Mode | Power |
|----|----|----|----------------|---------------------------|----------------------------|
| Н | Х | Х | High Z | Deselect/Power-down | Standby (I _{SB}) |
| L | Н | L | Data Out | Read | Active (I _{CC}) |
| L | L | Х | Data In | Write | Active (I _{CC}) |
| L | Н | Н | High Z | Deselect, Output disabled | Active (I _{CC}) |



Ordering Information

| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range | |
|---------------|------------------|---|--|--------------------|--|
| 8 | CY7C199-8VC | V21 | 28-Lead Molded SOJ | Commercial | |
| | CY7C199-8ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-8VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-8ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| 10 | CY7C199-10VC | V21 | 28-Lead Molded SOJ | Commercial | |
| | CY7C199-10ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-10VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-10ZC Z2 | | 28-Lead Thin Small Outline Package | | |
| | CY7C199-10VI | V21 | V21 28-Lead Molded SOJ Ind | | |
| | CY7C199-10ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-10VI | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-10ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| 12 | CY7C199-12PC | P21 | 28-Lead (300-Mil) Molded DIP | Commercial | |
| | CY7C199-12VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-12ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-12PC | P21 | 28-Lead (300-Mil) Molded DIP | | |
| | CY7C199L-12VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-12ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-12VI | V21 | 28-Lead Molded SOJ | Industrial | |
| | CY7C199-12ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-12VI | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-12ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| 15 | CY7C199-15PC | 7C199-15PC P21 28-Lead (300-Mil) Molded DIP | | Commercial | |
| | CY7C199-15VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-15ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-15PC | P21 | 28-Lead (300-Mil) Molded DIP | | |
| | CY7C199L-15VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-15ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-15VI | V21 | 28-Lead Molded SOJ | Industrial | |
| | CY7C199-15ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-15DMB | Y7C199-15DMB D22 28-Lead (300-Mil) CerDIP | | Military | |
| | CY7C199-15LMB | L54 | 28-Pin Rectangular Leadless Chip Carrier | | |
| | CY7C199L-15DMB | D22 | 28-Lead (300-Mil) CerDIP | | |
| | CY7C199L-15LMB | L54 | 28-Pin Rectangular Leadless Chip Carrier | | |
| 20 | CY7C199-20PC | P21 | 28-Lead (300-Mil) Molded DIP | Commercial | |
| | CY7C199-20VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-20ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199L-20PC | P21 | 28-Lead (300-Mil) Molded DIP | | |
| | CY7C199L-20VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199L-20ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-20VI | V21 | 28-Lead Molded SOJ | Industrial | |
| | CY7C199-20ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-20DMB | D22 | 28-Lead (300-Mil) CerDIP | Military | |
| | CY7C199-20LMB | L54 | 28-Pin Rectangular Leadless Chip Carrier | | |
| | CY7C199L-20DMB | D22 | 28-Lead (300-Mil) CerDIP | | |
| | CY7C199L-20LMB | | | | |

Shaded area contains advance information. Contact your Cypress sales representative for availability



Ordering Information (continued)

| Speed (ns) | | | Package Type | Operating Range | |
|------------|-------------------|-----|--|--------------------|--|
| 25 | CY7C199-25PC | P21 | 28-Lead (300-Mil) Molded DIP | Commercial | |
| | CY7C199-25SC | S21 | 28-Lead Molded SOIC | | |
| | CY7C199-25VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-25ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-25SI | S21 | 28-Lead Molded SOIC | Industrial | |
| | CY7C199-25VI | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-25ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-25DMB | D22 | 28-Lead (300-Mil) CerDIP | Military | |
| | CY7C199-25LMB | L54 | 28-Pin Rectangular Leadless Chip Carrier | | |
| 35 | CY7C199-35PC | P21 | 28-Lead (300-Mil) Molded DIP | Commercial | |
| | CY7C199-35SC | S21 | 28-Lead Molded SOIC | | |
| | CY7C199-35VC | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-35ZC | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-35SI | S21 | 28-Lead Molded SOIC | Industrial | |
| | CY7C199-35VI | V21 | 28-Lead Molded SOJ | | |
| | CY7C199-35ZI | Z28 | 28-Lead Thin Small Outline Package | | |
| | CY7C199-35DMB | D22 | 28-Lead (300-Mil) CerDIP | Military | |
| | CY7C199-35LMB | L54 | 28-Pin Rectangular Leadless Chip Carrier | | |
| 45 | CY7C199-45DMB D22 | | 28-Lead (300-Mil) CerDIP | Military | |
| | CY7C199-45LMB | L54 | 28-Pin Rectangular Leadless Chip Carrier | | |

Shaded area contains advance information. Contact your Cypress sales representative for availability

MILITARY SPECIFICATIONS Group A Subgroup Testing

DC Characteristics

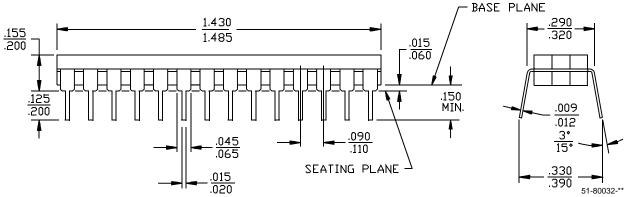
| Parameter | Subgroups |
|----------------------|-----------|
| V _{OH} | 1, 2, 3 |
| V _{OL} | 1, 2, 3 |
| V _{IH} | 1, 2, 3 |
| V _{IL} Max. | 1, 2, 3 |
| l _{IX} | 1, 2, 3 |
| I _{OZ} | 1, 2, 3 |
| I _{CC} | 1, 2, 3 |
| I _{SB1} | 1, 2, 3 |
| I _{SB2} | 1, 2, 3 |

Switching Characteristics

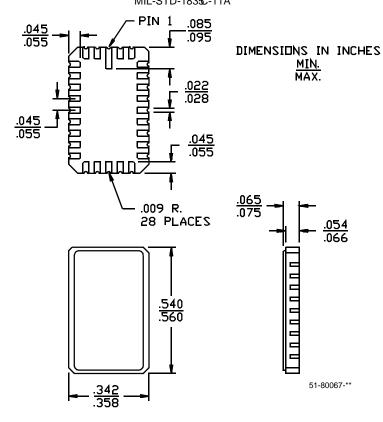
| Parameter | Subgroups | |
|------------------|-----------------|--|
| Read Cycle | | |
| t _{RC} | 7, 8, 9, 10, 11 | |
| t _{AA} | 7, 8, 9, 10, 11 | |
| t _{OHA} | 7, 8, 9, 10, 11 | |
| t _{ACE} | 7, 8, 9, 10, 11 | |
| t _{DOE} | 7, 8, 9, 10, 11 | |
| Write Cycle | | |
| t _{WC} | 7, 8, 9, 10, 11 | |
| t _{AA} | 7, 8, 9, 10, 11 | |
| t _{AW} | 7, 8, 9, 10, 11 | |
| t _{HA} | 7, 8, 9, 10, 11 | |
| t _{SA} | 7, 8, 9, 10, 11 | |
| t _{PWE} | 7, 8, 9, 10, 11 | |
| t _{SD} | 7, 8, 9, 10, 11 | |
| t _{HD} | 7, 8, 9, 10, 11 | |



Package Diagrams



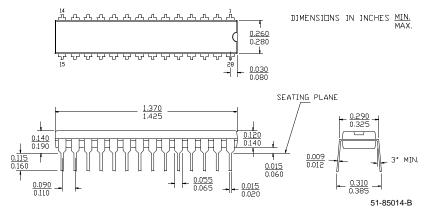
28-pin Rectangular Leadless Chip Carrier L54 MIL-STD-183\$C-11A



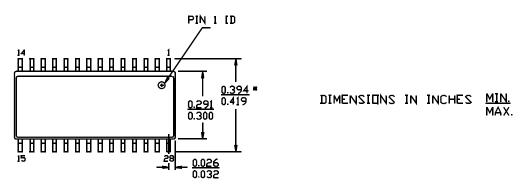


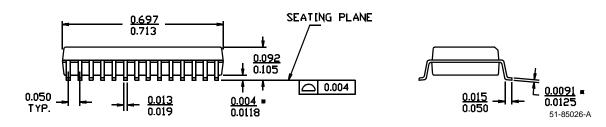
Package Diagrams (continued)

28-pin (300-Mil) Molded DIP P21



28-pin (300-Mil) Molded SOIC S21

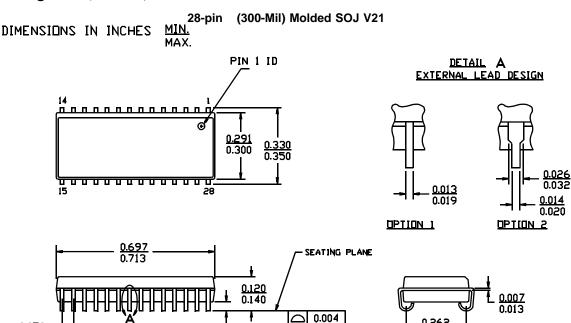




51-85031-B



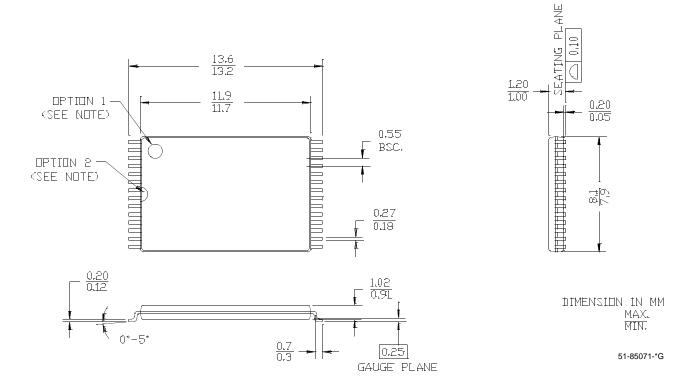
Package Diagrams (continued)



28-Lead Thin Small Outline Package Type 1 (8x13.4 mm) Z28

0.025 MIN.

NDTE: ORIENTATION I.D MAY BE LOCATED EITHER
AS SHOWN IN OPTION 1 OR OPTION 2



All products and company names mentioned in this document are the trademarks of their respective holders.



Document History Page

| Document Title: CY7C199 32K x 8 Static RAM Document Number: 38-05160 | | | | |
|--|---------|---------------|--------------------|---|
| REV. | ECN NO. | Issue Date | Orig. of Change | Description of Change |
| ** | 109971 | 10/28/01 | SZV | Change from Spec number: 38-00239 to 38-05160 |
| *A | 121730 | 01/09/02 | DFP | Updated Product Offering table. |